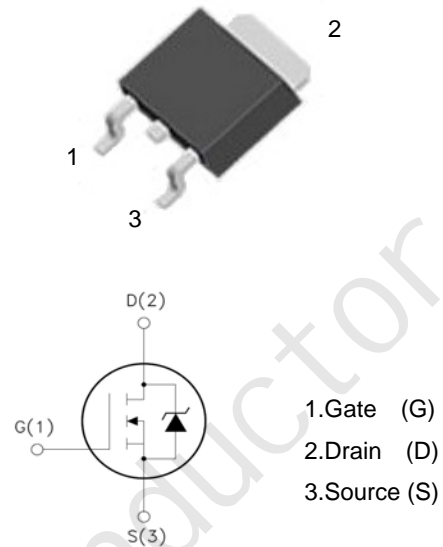


Features:

- 1.0A, 650V, $R_{DS(on)} = 11.0 \Omega @ V_{GS} = 10 \text{ V}$
- Low gate charge
- Low C_{rss}
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability

TO-252

Absolute Maximum Ratings ($T_a=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Value	Unit
V_{DSS}	Drain-Source Voltage	650	V
I_D	Drain Current	$T_C=25^\circ\text{C}$	1
		$T_C=100^\circ\text{C}$	0.63
$V_{GS(TH)}$	Gate Threshold Voltage	± 30	V
E_{AS}	Single Pulse Avalanche Energy (note1)	50	mJ
I_{AR}	Avalanche Current (note2)	1	A
P_D	Power Dissipation ($T_a=25^\circ\text{C}$)	28	W
T_j	Junction Temperature(Max)	150	°C
T_{stg}	Storage Temperature	-55~+150	
TL	Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds	300	

Thermal Characteristics

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case	-	4.17	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	-	50	°C/W

Electrical Characteristics $T_c=25^{\circ}\text{C}$ unless other wise noted

Symbol	Parameter	Test Condition	Min.	Typ.	Max	Units
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\ \mu\text{A}, V_{GS}=0$	650	--	--	V
$\Delta BV_{DSS}/\Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D=250\ \mu\text{A}$, Reference to 25°C	--	0.4	--	$\text{V}/^{\circ}\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=600\text{V}, V_{GS}=0\text{V}$	--	--	1	μA
		$V_{DS}=480\text{V}, T_c=125^{\circ}\text{C}$	--	--	10	μA
I_{GSSF}	Gate-body leakage Current, Forward	$V_{GS}=+30\text{V}, V_{DS}=0\text{V}$	--	--	100	nA
I_{GSSR}	Gate-body leakage Current, Reverse	$V_{GS}=-30\text{V}, V_{DS}=0\text{V}$	--	--	-100	nA
On Characteristics						
$V_{GS(th)}$	Gate Threshold Voltage	$I_D=250\ \mu\text{A}, V_{DS}=V_{GS}$	2	--	4	V
$R_{DS(on)}$	Static Drain-Source On-Resistance	$I_D=0.5\text{A}, V_{GS}=10\text{V}$	--	--	11	Ω
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS}=25\text{V}, V_{GS}=0,$ $f=1.0\text{MHz}$	--	120	150	pF
C_{oss}	Output Capacitance		--	25	60	pF
C_{rss}	Reverse Transfer Capacitance		--	3	4	pF
Switching Characteristics						
$T_d(on)$	Turn-On Delay Time	$V_{DD}=300\text{V}, I_D=1\text{A},$ $R_G=25\ \Omega$ (Note 3,4)	--	5	20	nS
T_r	Turn-On Rise Time		--	25	60	nS
$T_d(off)$	Turn-Off Delay Time		--	7	25	nS
T_f	Turn-Off Fall Time		--	25	60	nS
Q_g	Total Gate Charge	$V_{DS}=480, V_{GS}=10\text{V},$ $I_D=2\text{A}$ (Note 3,4)	--	5	6	pF
Q_{gs}	Gate-Source Charge		--	1	--	nC
Q_{gd}	Gate-Drain Charge		--	2.6	--	nC
Drain-Source Diode Characteristics and Maximum Ratings						
I_S	Maximun Continuous Drain-Source Diode Forward Current		--	--	1	A
I_{SM}	Maximun Plused Drain-Source Diode Forward Current		--	--	4	A
V_{SD}	Drain-Source Diode Forward Voltage	$I_D=1\text{A}$	--	--	1.4	V
t_{rr}	Reverse Recovery Time	$I_S=2\text{A}, V_{GS}=0\text{V}$	--	160	--	nS
Q_{rr}	Reverse Recovery Charge	$di_F/dt=100\text{A}/\mu\text{S}$ (Note3)	--	0.30	--	μC

- *Notes
- 1, $L=55\text{mH}, I_{AS}=1\text{A}, V_{DD}=50\text{V}, R_G=25\ \Omega$, Starting $T_J=25^{\circ}\text{C}$
 - 2, Repetitive Rating : Pulse width limited by maximum junction temperature
 - 3, Pulse Test : Pulse Width $\leq 300\ \mu\text{s}$, Duty Cycle $\leq 2\%$
 - 4, Essentially Independent of Operating Temperature

Typical Characteristics

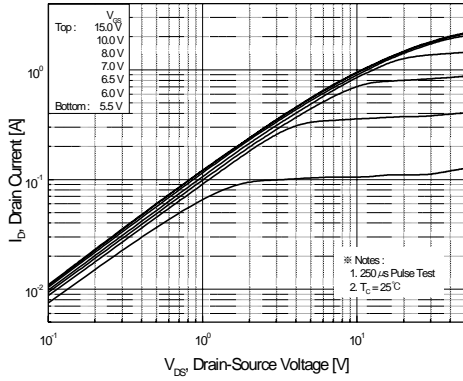


Figure 1. On-Region Characteristics

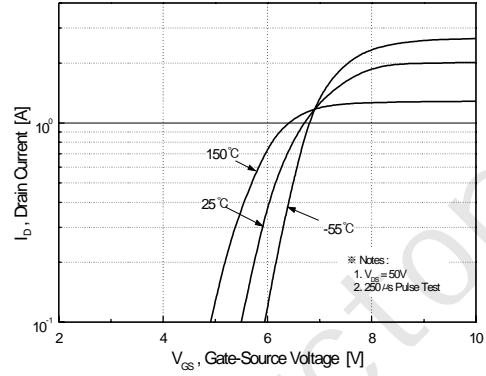


Figure 2. Transfer Characteristics

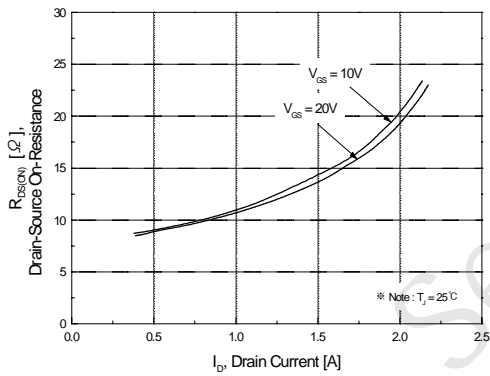


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

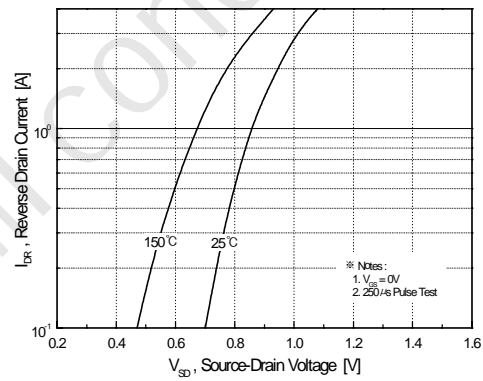


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

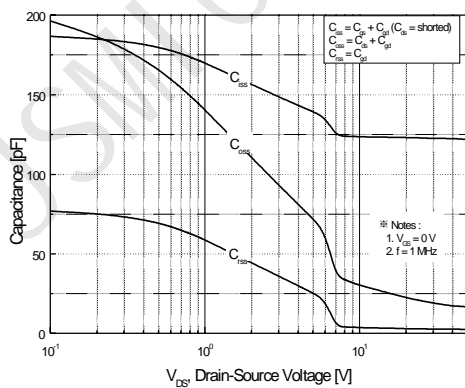


Figure 5. Capacitance Characteristics

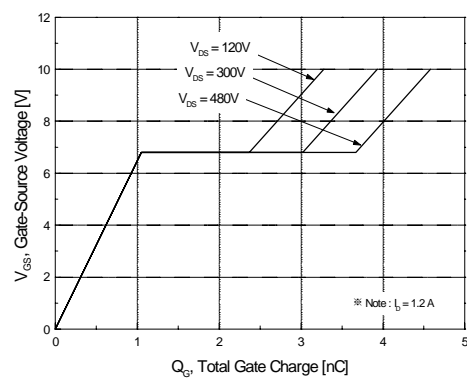


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)

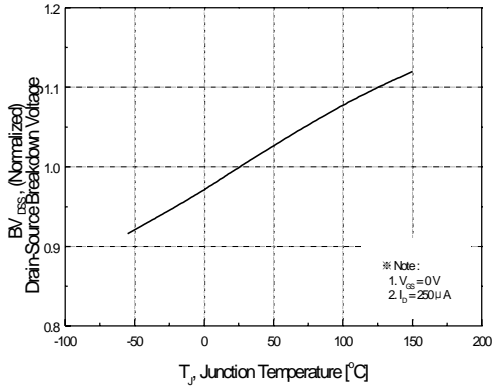


Figure 7. Breakdown Voltage Variation vs. Temperature

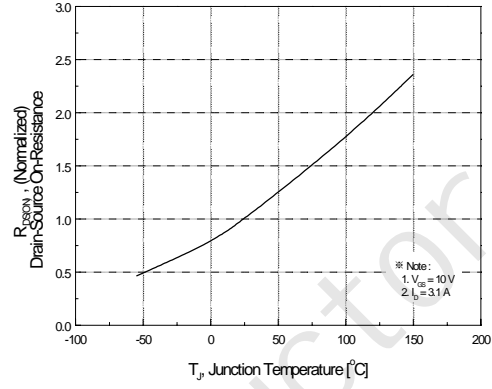


Figure 8. On-Resistance Variation vs. Temperature

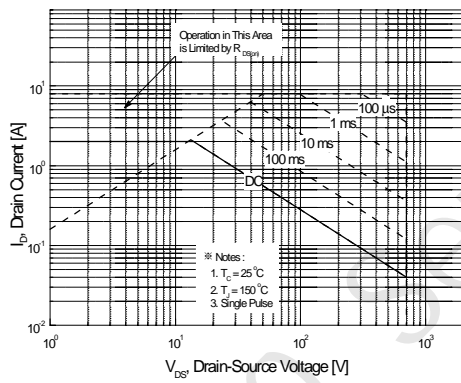


Figure 9. Maximum Safe Operating Area

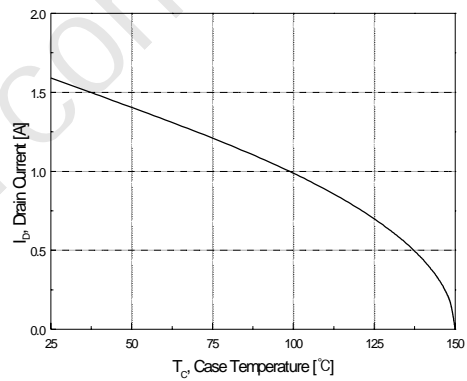


Figure 10. Maximum Drain Current vs. Case Temperature

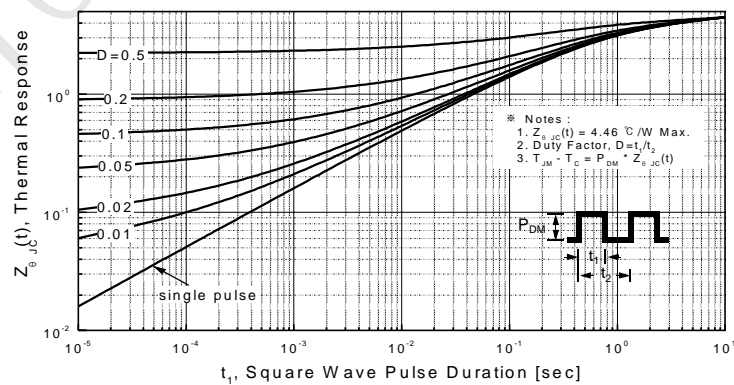
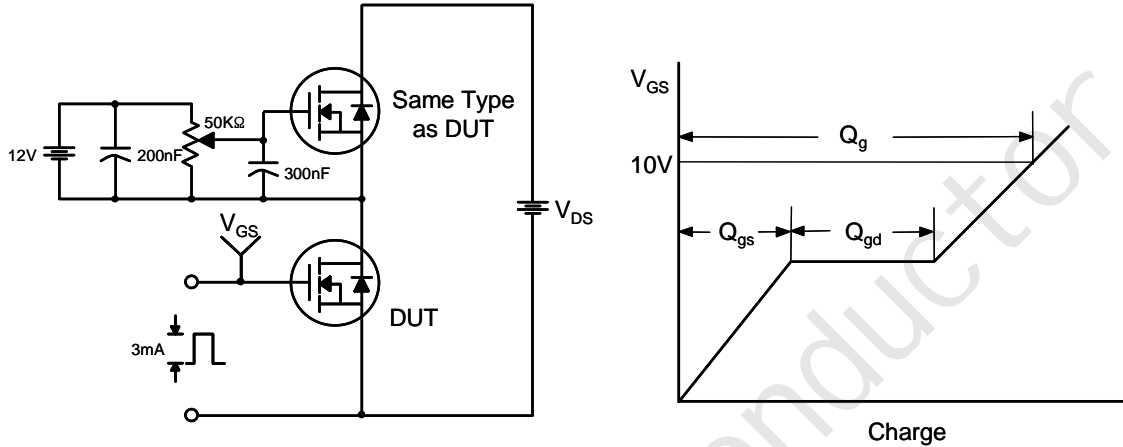
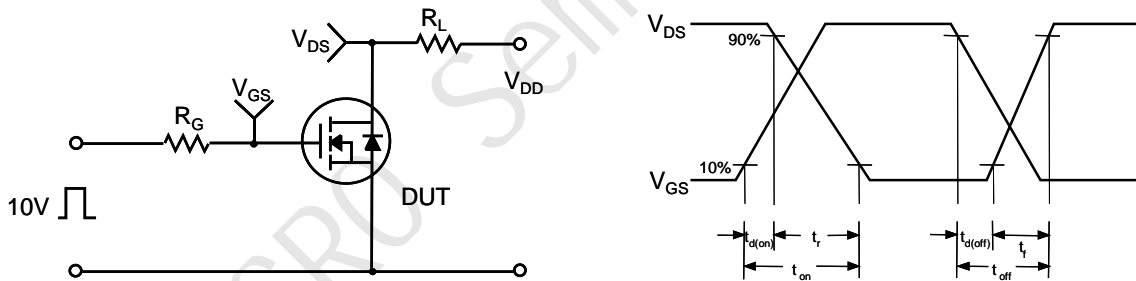
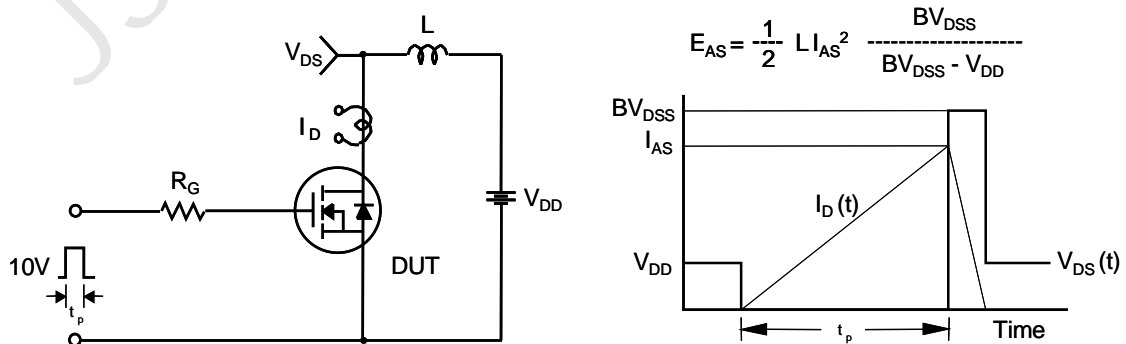
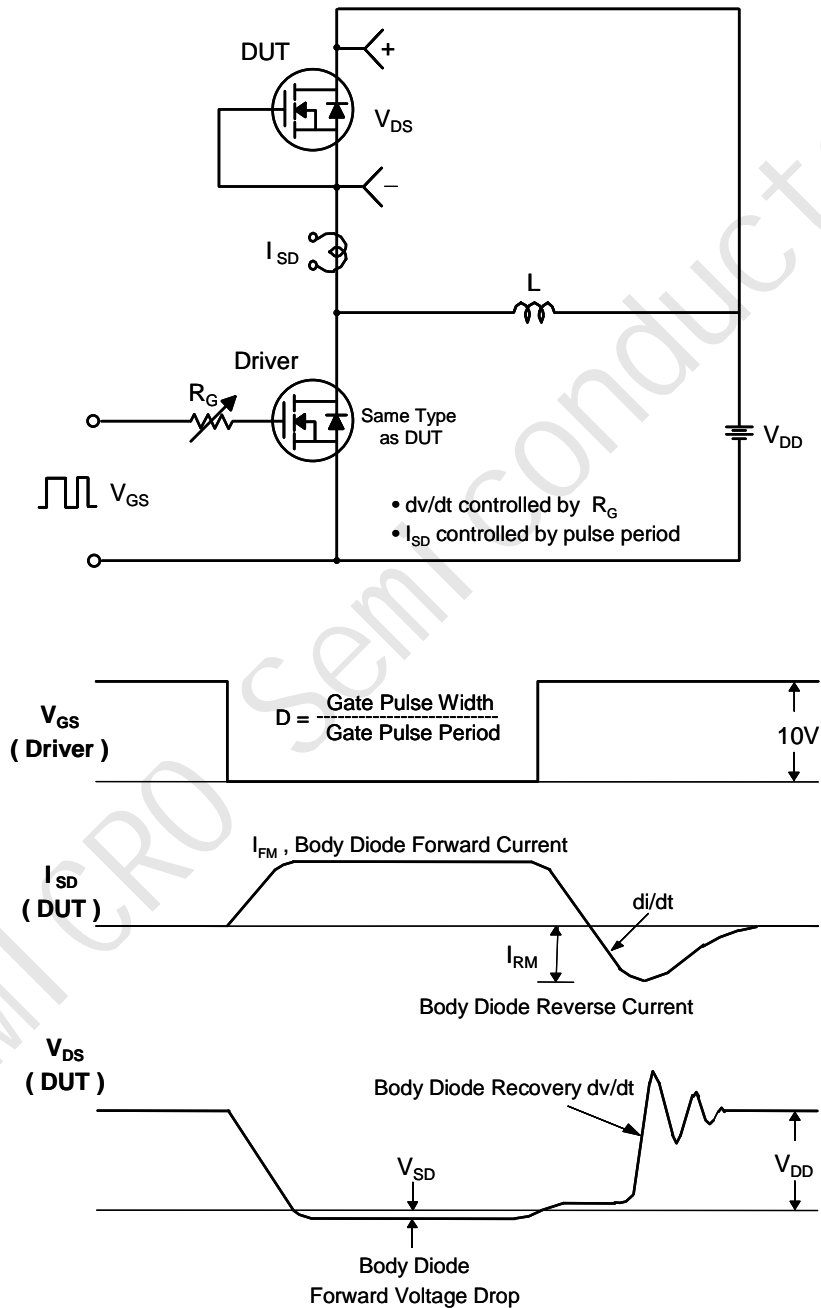


Figure 11. Transient Thermal Response Curve

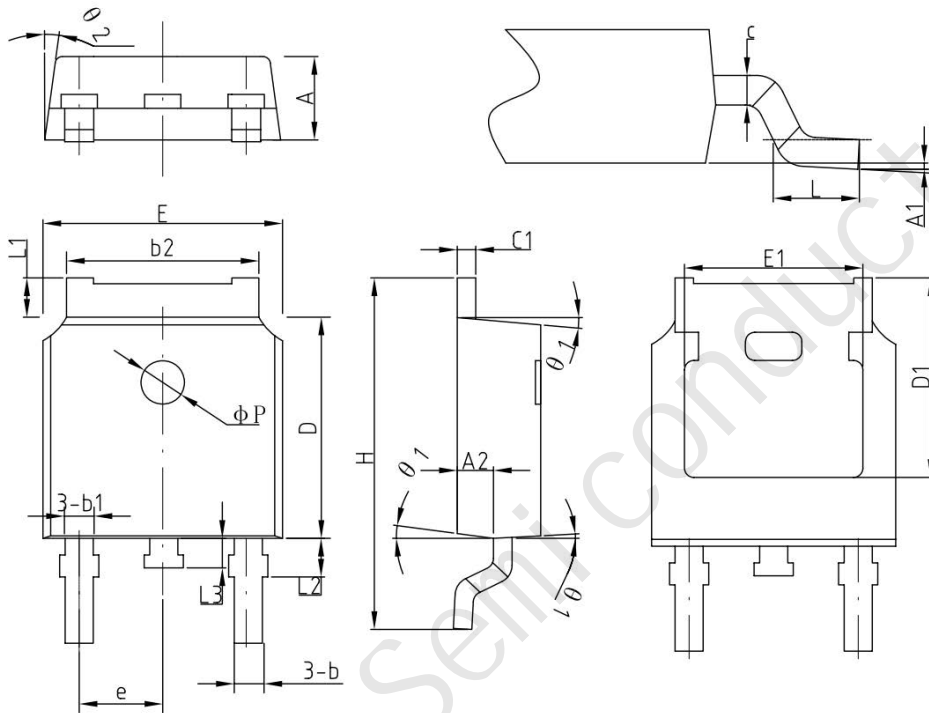
Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching Test Circuit & Waveforms


Peak Diode Recovery dv/dt Test Circuit & Waveforms



Package Dimension
TO-252

Units: mm


 COMMON DIMENSIONS
 (UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	NOM	MAX
A	2.2	2.30	2.38
A1	0	—	0.10
A2	0.90	1.01	1.10
b	0.71	0.76	0.86
b1		0.76	
b2	5.13	5.33	5.46
c	0.47	0.50	0.60
c1	0.47	0.50	0.60
D	6.0	6.10	6.20
D1	—	5.30	—
E	6.50	6.60	6.70
E1	—	4.80	—
e	2.286BSC		
H	9.70	10.10	10.40
L	1.40	1.50	1.70
L1	0.90	—	1.25
L2		1.05	
L3		0.8	
φP		1.2	
θ	0°	—	8°
θ 1	5°	7°	9°
θ 2	5°	7°	9°